

WIREBONDS STATUS

dE				E-front				E-back				Last checked	
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	date	detector
1				1				1				10/1/07	dE, Ef, Eb
2				2				2					
3				3				3					
4				4				4					
5				5				5					
6				6				6					
7				7				7					
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30				30				30					
31				31				31					
32				32				32					

Legend:

X = bond missing / = bond broken ~ = bond damaged

T2210

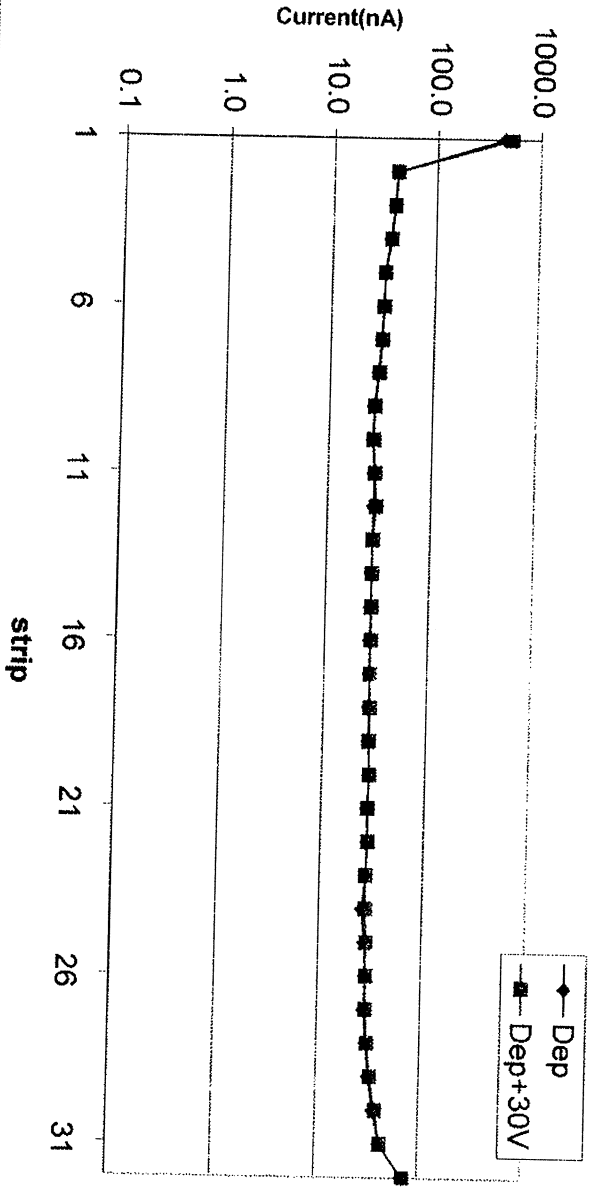
AE = 2297-9
E = 2893-14

Wafer No.: 2393-14 Thickness: 1511 um Depletion: 180 Volts

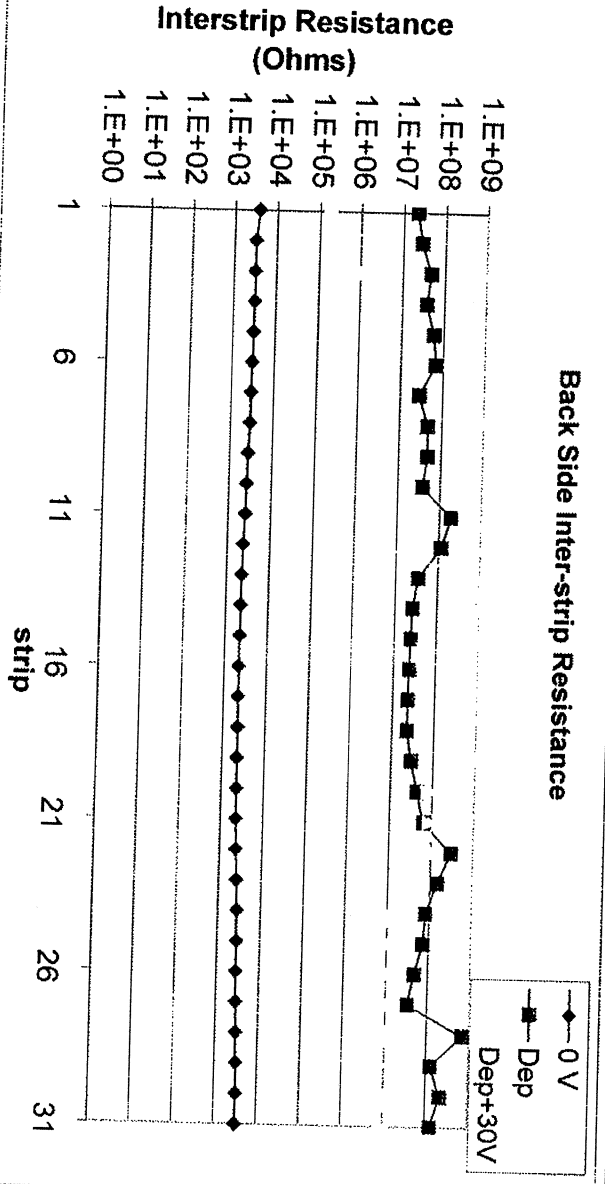
Front Side Data

Strip	Current(nA)	Dep+30V
1	453.60	525.40
2	41.20	41.40
3	39.00	39.80
4	35.90	36.50
5	32.20	32.50
6	31.30	31.90
7	30.70	31.20
8	29.10	29.40
9	26.90	27.40
10	26.50	27.00
11	27.80	28.10
12	27.70	29.20
13	27.60	27.70
14	27.30	27.60
15	27.20	27.80
16	27.20	28.00
17	27.30	27.70
18	27.30	28.30
19	27.80	27.90
20	28.40	28.60
21	27.70	28.20
22	28.30	28.60
23	27.70	27.80
24	26.00	27.90
25	27.80	28.80
26	28.60	29.00
27	30.10	29.20
28	30.10	30.70
29	31.90	33.00
30	36.10	37.90
31	41.90	42.50
32	70.80	71.40
total	1427.00	1518.49

Front Side Strip Leakage Current



Back Side Inter-strip Resistance



Back Side Data

Strip	0V	Dep	Dep+30V
1	3.8E+03	2.2E+07	1.8E+05
2	3.2E+03	2.8E+07	1.7E+06
3	3.2E+03	4.7E+07	1.5E+06
4	3.1E+03	3.9E+07	1.8E+06
5	3.1E+03	5.9E+07	2.1E+06
6	3.0E+03	6.8E+07	2.3E+06
7	2.9E+03	2.9E+07	2.2E+06
8	2.9E+03	4.7E+07	2.5E+06
9	2.7E+03	4.9E+07	3.1E+06
10	2.6E+03	3.9E+07	4.5E+06
11	2.4E+03	1.2E+08	5.3E+06
12	2.4E+03	1.2E+08	4.9E+06
13	2.3E+03	3.5E+07	8.7E+08
14	2.3E+03	2.6E+07	8.8E+08
15	2.2E+03	2.5E+07	8.3E+08
16	2.2E+03	2.4E+07	4.4E+08
17	2.2E+03	2.3E+07	1.4E+09
18	2.2E+03	2.3E+07	1.4E+09
19	2.3E+03	3.0E+07	9.1E+08
20	2.3E+03	4.3E+07	8.1E+07
21	2.3E+03	6.3E+07	8.9E+07
22	2.5E+03	3.0E+08	1.2E+08
23	2.6E+03	1.5E+08	2.2E+07
24	2.8E+03	8.2E+07	9.9E+06
25	2.8E+03	7.3E+07	1.2E+07
26	2.8E+03	4.7E+07	1.2E+07
27	2.9E+03	3.4E+07	1.2E+07
28	3.0E+03	6.9E+08	1.0E+07
29	3.2E+03	1.3E+08	8.3E+06
30	3.3E+03	2.2E+08	9.6E+06
31	3.2E+03	1.3E+08	8.9E+06

Resolution Test

HIRA BB7

Wafer No.: **2393-14**

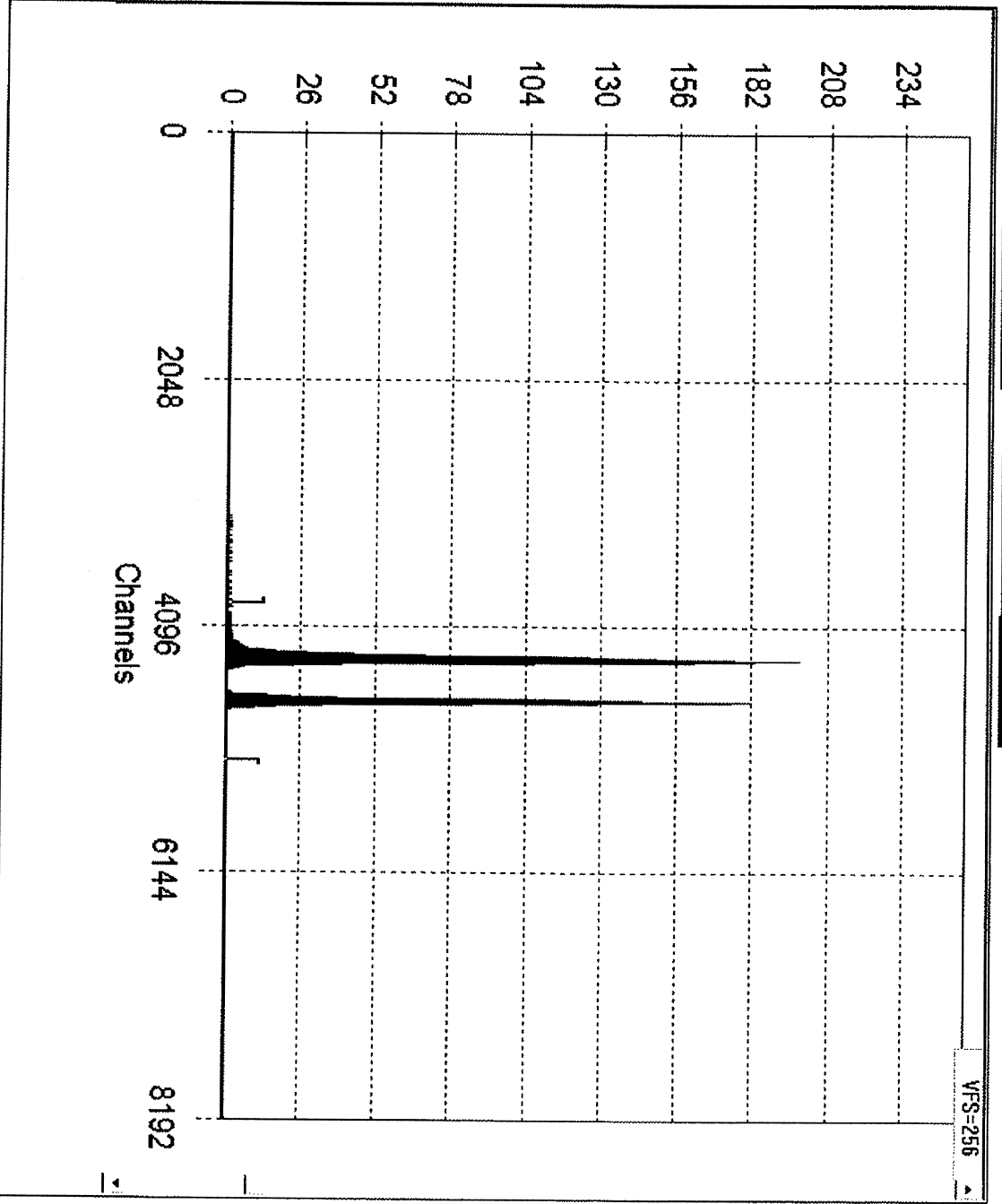
Thickness: **1511** μm

JUNCTION

DET LINE: **68.9** KeV
SYSTEM: **47.7** KeV
CAL: **49.7** KeV

OHMIC

DET LINE: **69.5** KeV
SYSTEM: **47.6** KeV
CALC: **50.6** KeV



BIAS VOLTS= / V

Leakage **1300** nA

Source
Am 241

Rise Time
 1

Flat Top
 0

Si-detector Inspection Record

Date: 10/1/2007

Time: 19:00 pm

Tel n.: 10

Inspected detector(s): dE(2297-9), E(2393-14)
dE removed

1st inspector: Vlad HENZL

2nd inspector: Daniela HENZLOVA

WIREBONDS STATUS

dE				E-front				E-back			
strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd	strip n.:	1st	2nd	3rd
1				1				1			
2				2				2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
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10				10				10			
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30				30				30			
31				31				31			
32				32				32			

Legend:

X = bond missing

/ = bond broken

~ = bond damaged

Overall detector status:

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)

dE, E_a wirebonds look good

E_b - scratch (small) between 20 and 21 strips

E_b wirebonds look good

Noise tests of detector n.: 2393-14 in telescope n.: 10

Date		2-2-07	10-10-07	10-31-07							
electronics		CLASSIC	CHIP	CHIP							
E back	Chip 0 or shaper 0	chn 0	~6mV	37mV	~37mV						
		1	4.5	30	36						
		2	4.5	30	36						
		3	4.5	30	36						
		4	~6mV	30	36						
		5	5	30	36						
		6	5	105mV	~90mV						
		7	5	150mV	~155mV						
		8	5	160mV	~155mV						
		9	5	115mV	~105mV						
		10	5	12mV	~40mV						
		11	5	33	39						
		12	5	31	39						
		13	5	30	36						
		14	5	30	36						
	15	~11mV	30	36							
	Chip 1 or shaper 1	chn 0	~11mV	30	36						
		1	5	30	36						
		2	5	30	36						
		3	5	30	36						
		4	~6mV	30	36						
		5	~6mV	30	36						
		6	5	160mV	~165mV						
		7	~6mV	160mV	~160mV						
		8	~7mV	150mV	~160mV						
		9	5	85mV	~45mV						
		10	5	33mV	32						
		11	5	32	32						
		12	5	31	32						
		13	5	30	32						
14		5	30	32							
15	~7mV	32	32								
E front	Chip 0 or shaper 2	chn 0	~10mV	32	~300mV						
		1	~7.5	45mV	31						
		2	8.5	27	31						
		3	8.5	30	31						
		4	9	28	31						
		5	~12.5mV	26	31						
		6	8	26	31						
		7	6	26	31						
		8	8.5	26	35						
		9	7.5	26	35						
		10	7.5	26	35						
		11	7.5	26	~48mV						
		12	~13mV	26	~60mV						
		13	~10mV	26	35						
		14	~20mV	26	~65mV						
	15	~16mV	26	~60mV							
	Chip 1 or shaper 3	chn 0	15mV	40	~33						
		1	6.5/15	26	31						
		2	6.5	45mV	31						
		3	6.5	45mV	31						
		4	6.5	26	31						
		5	6.5	26	31						
		6	6.5	26	~160mV						
		7	6.5	26	~170mV						
		8	6.5	26	33						
		9	6.5	26	35						
		10	6.5	26	33						
		11	6.5	26	33						
		12	15mV	26	~15mV						
		13	20mV	26	~47mV						
14		6.5	26	~60mV							
15	20mV	35mV	~115mV								

identical setup before and after 1st part of 05/03

Si-detector Inspection Record

Date: 10/05/2007

Time: 7:00pm

Tel n.: 10

Inspected detector(s): dE(2297-9) put back in place
Ef

1st inspector: Vlad HENZL

2nd inspector: Dawida HENZLOVA

WIREBONDS STATUS

dE				E-front				E-back			
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1				1				1			
2				2				2			
3				3				3			
4				4				4			
5				5				5			
6				6				6			
7				7				7			
8				8				8			
9				9				9			
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29				29				29			
30				30				30			
31				31				31			
32				32				32			

Legend:

X = bond missing / = bond broken ~ = bond damaged

Overall detector status:

(e.g. dusty surface, scratches, dirty frame and/or cable, status of telescope can ...)

Ef - scratch between 21st and 22nd strips
Ef wirebonds look good; Ef sample blown with dry Ni
dE wirebonds look good